



SANYO Semiconductors

DATA SHEET

MCH3109 / MCH3209

 — PNP / NPN Epitaxial Planar Silicon Transistors
DC / DC Converter Applications

Applications

- Relay drivers, lamp drivers, motor drivers, flash.

Features

- Adoption of MBIT processes.
- High current capacitance.
- Low collector-to-emitter saturation voltage.
- High-speed switching.
- Ultrasmall package facilitates miniaturization in end products (mounting height : 0.85mm).
- High allowable power dissipation.

Specifications () : MCH3109

Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Collector-to-Base Voltage	V _{CB0}		(-30)40	V
Collector-to-Emitter Voltage	V _{CE0}		(-30)	V
Emitter-to-Base Voltage	V _{EB0}		(-5)	V
Collector Current	I _C		(-3)	A
Collector Current (Pulse)	I _{CP}		(-5)	A
Base Current	I _B		(-600)	mA
Collector Dissipation	P _C	Mounted on a ceramic board (600mm ² X0.8mm)	0.8	W
Junction Temperature	T _J		150	°C
Storage Temperature	T _{stg}		-55 to +150	°C

Electrical Characteristics

 at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
Collector Cutoff Current	I _{CB0}	V _{CB} =(-)30V, I _E =0A			(-)0.1	μA
Emitter Cutoff Current	I _{EB0}	V _{EB} =(-)4V, I _C =0A			(-)0.1	μA
DC Current Gain	h _{FE}	V _{CE} =(-)2V, I _C =(-)500mA	200		560	
Gain-Bandwidth Product	f _T	V _{CE} =(-)10V, I _C =(-)500mA		(380)450		MHz
Output Capacitance	C _{ob}	V _{CB} =(-)10V, f=1MHz		(25)20		pF

Marking : MCH3109 : AJ / MCH3209 : CJ

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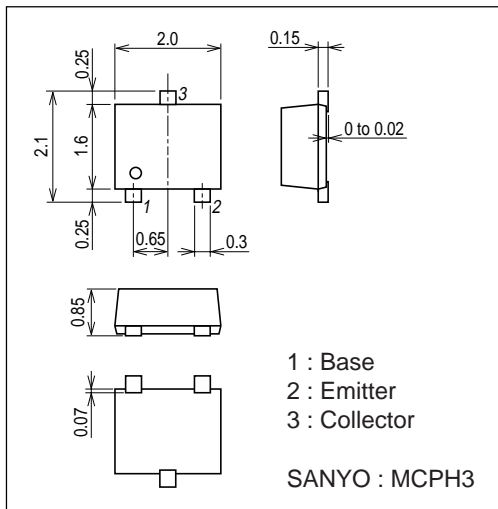
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Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
Collector-to-Emitter Saturation Voltage	$V_{CE(sat)1}$	$I_C = (-)1.5A, I_B = (-)30mA$		(-155)	(-230)	mV
	$V_{CE(sat)2}$	$I_C = (-)1.5A, I_B = (-)75mA$		120	180	mV
Base-to-Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C = (-)1.5A, I_B = (-)30mA$		(-)105	(-)155	mV
Collector-to-Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C = (-)10\mu A, I_E = 0A$	(-30)40			V
Collector-to-Emitter Breakdown Voltage	$V_{(BR)CEO}$	$I_C = (-)1mA, R_{BE} = \infty$	(-)30			V
Emitter-to-Base Breakdown Voltage	$V_{(BR)EBO}$	$I_E = (-)10\mu A, I_C = 0A$	(-)5			V
Turn-ON Time	t_{on}	See specified Test Circuit.		(50)30		ns
Storage Time	t_{stg}	See specified Test Circuit.		(270)300		ns
Fall Time	t_f	See specified Test Circuit.		(25)15		ns

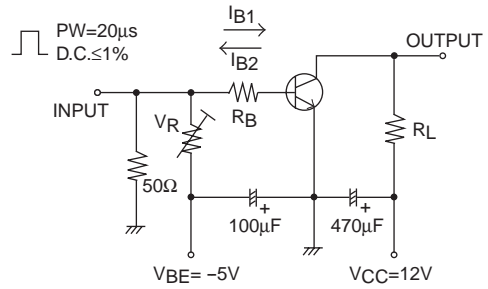
Package Dimensions

unit : mm

7019A-004

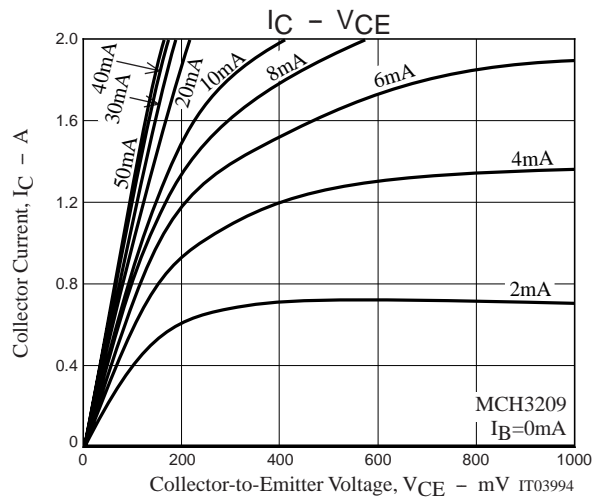
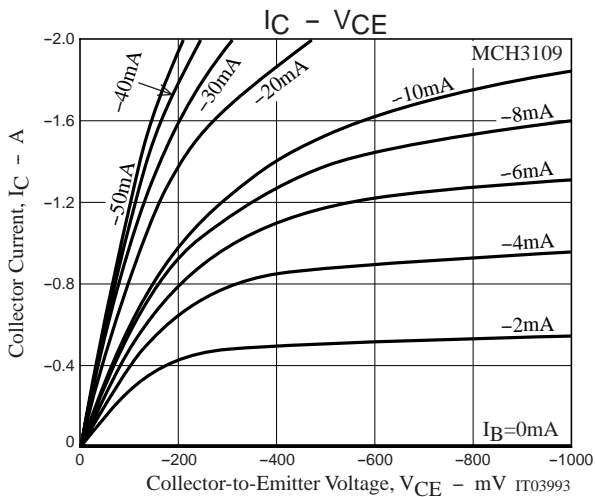


Switching Time Test Circuit

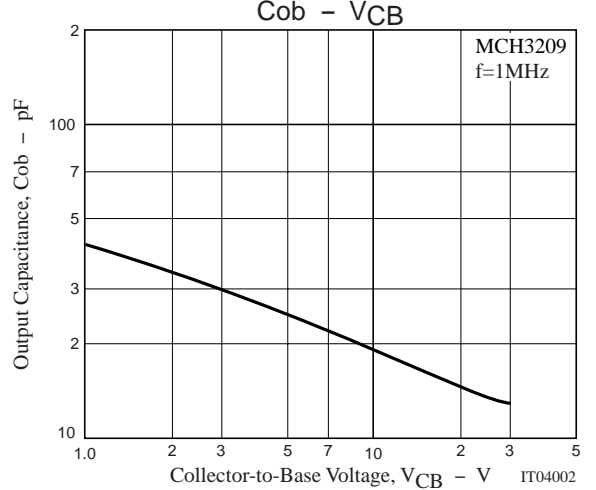
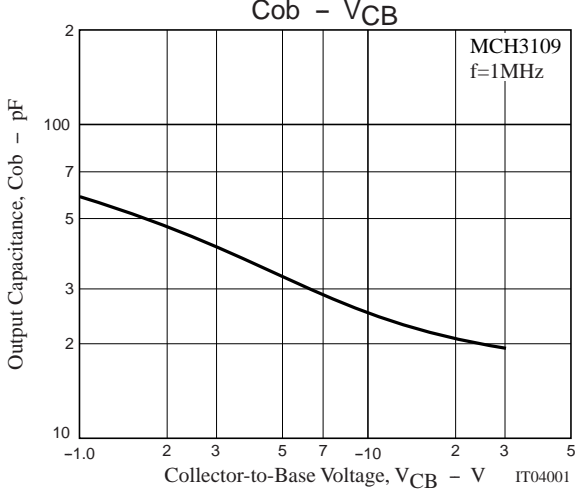
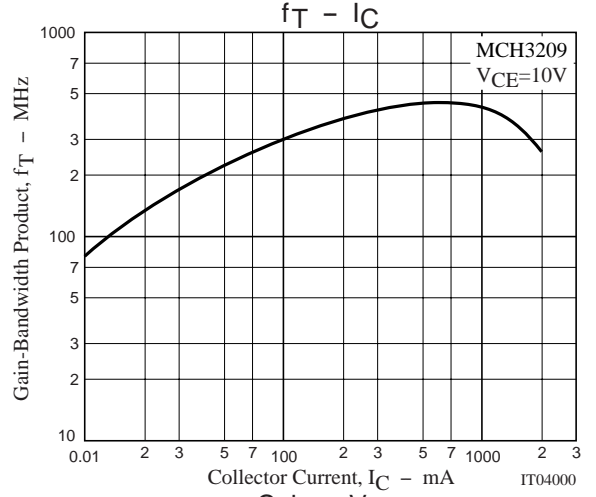
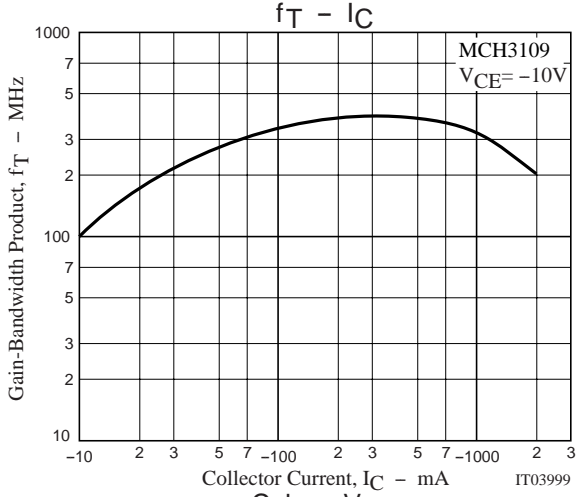
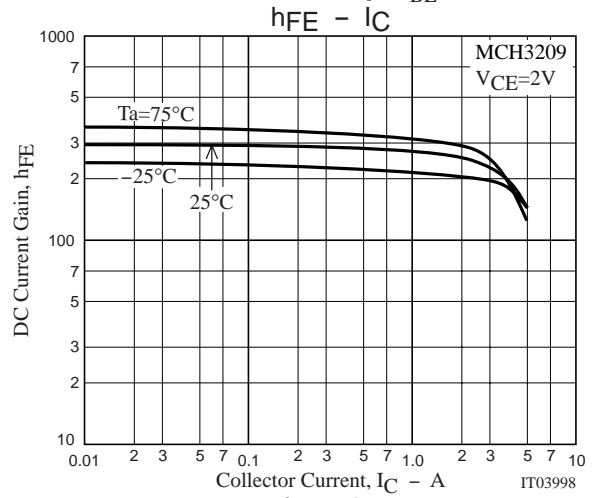
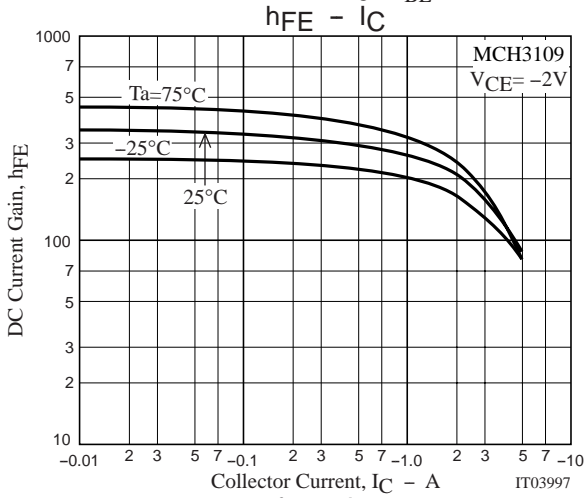
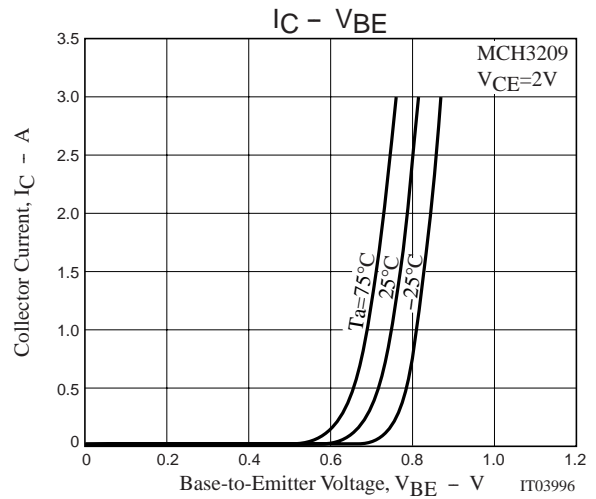
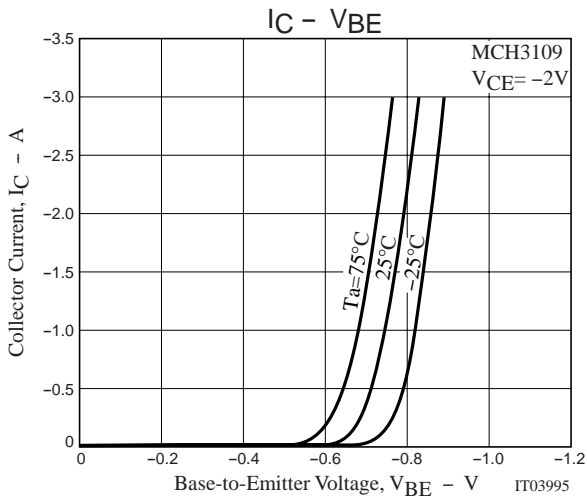


$$I_C = 20I_{B1} = -20I_{B2} = 500mA$$

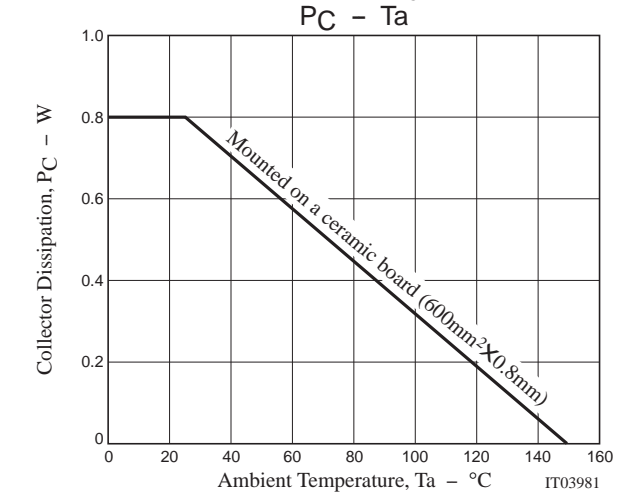
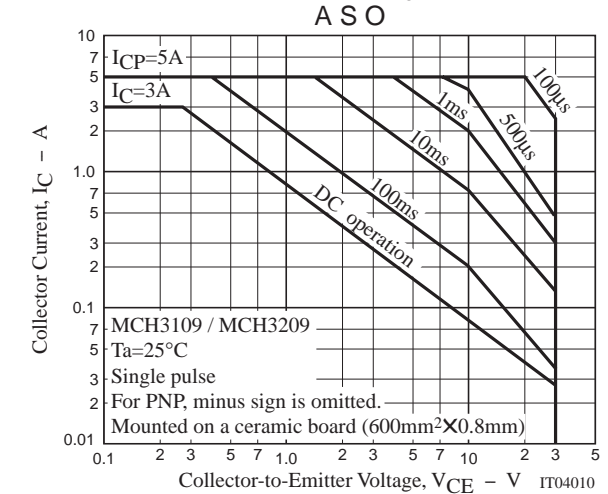
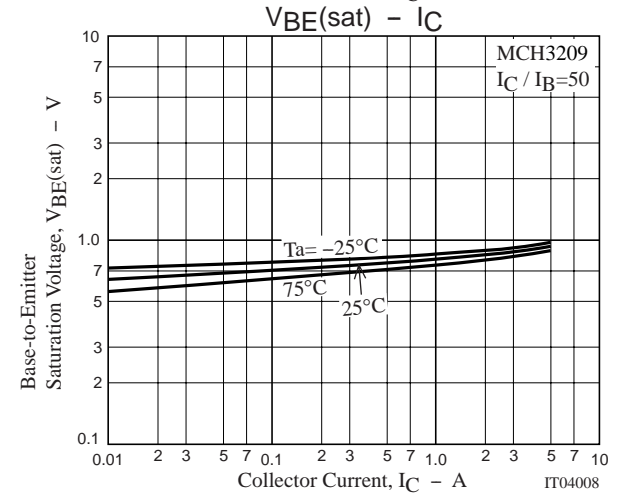
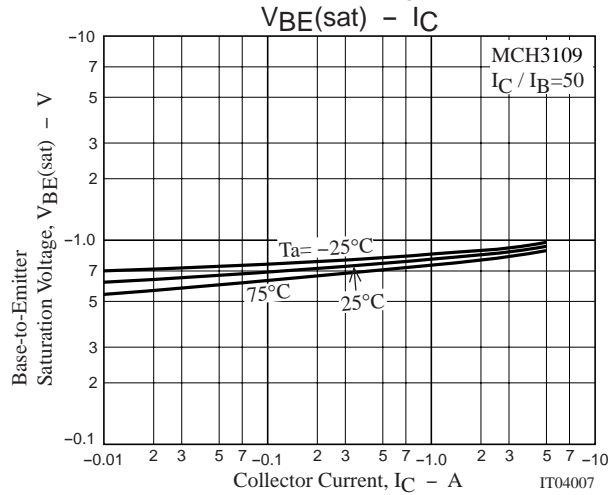
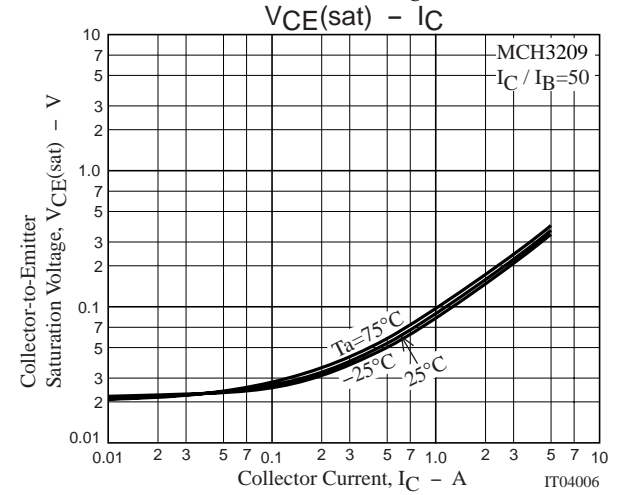
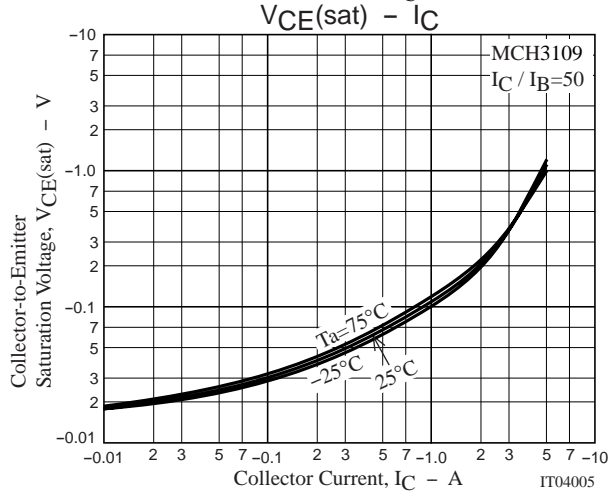
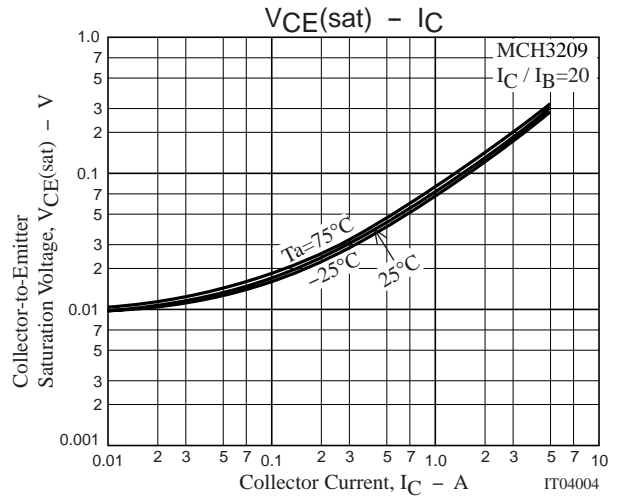
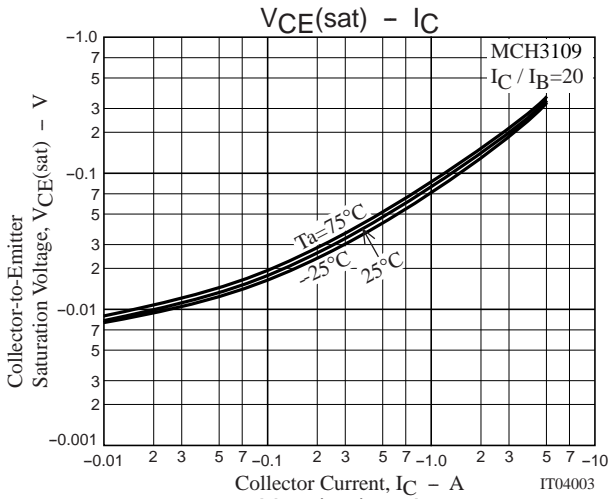
(For PNP, the polarity is reversed.)



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